Se	arch N	otes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/630,999	BODIN ET AL.
Examiner	Art Unit

2616

Syed Zaidi

SEARCHED				
Class	Subclass	Date	Examiner	
370	229	12/5/2007	sz	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	12/5/2007	· SZ
Inventor : Bodin et al.	12/05/07	SZ
Consulted with SPE Seema Rao	12/05/07	SZ
(370/229 370/221 370/222 370/224 370/225 370/226 370/228).CCLS.	12/05/07	SZ
(IEEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	12/5/2007	SZ